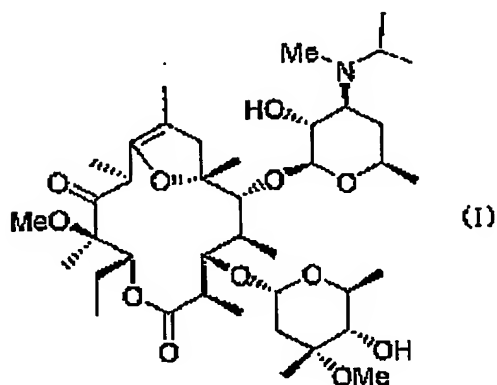


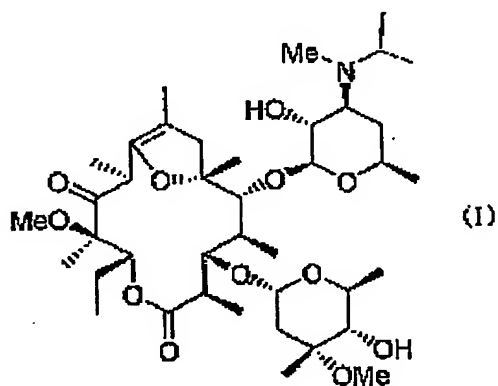
Claims

1. A hemifumarate crystal of a compound of formula (I):



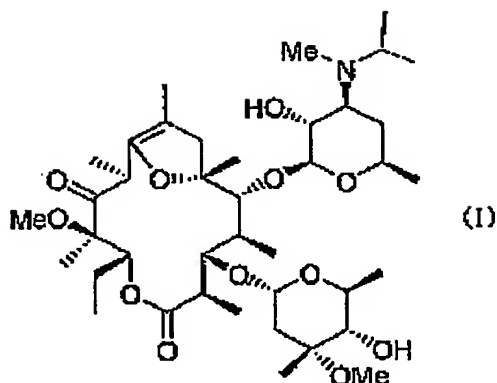
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°.

2. A hemifumarate anhydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°.

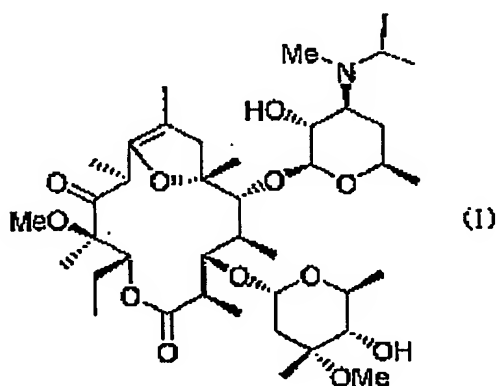
3. A hemifumarate X-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2° .

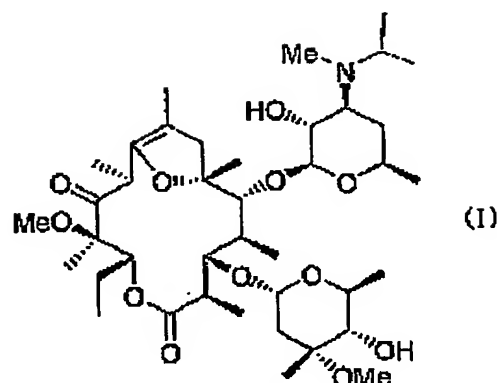
4. A process for preparing a hemifumarate X-hydrate of a compound of formula

5 (I):



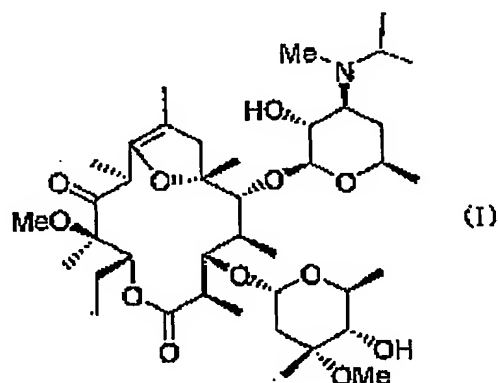
10 characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , to obtain said hemifumarate X-hydrate.

5. A process for preparing a hemifumarate anhydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of treating a hemifumarate crystal form of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, to obtain said hydrate.

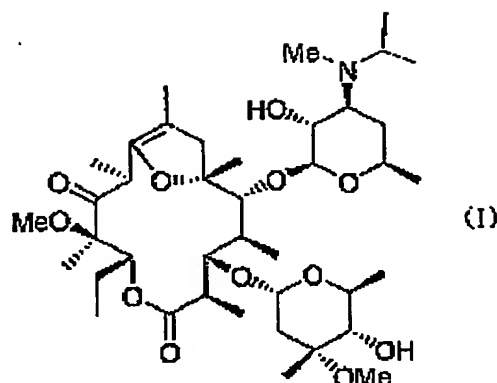
6. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) 6.6° and 8.5°, to obtain said hydrate.

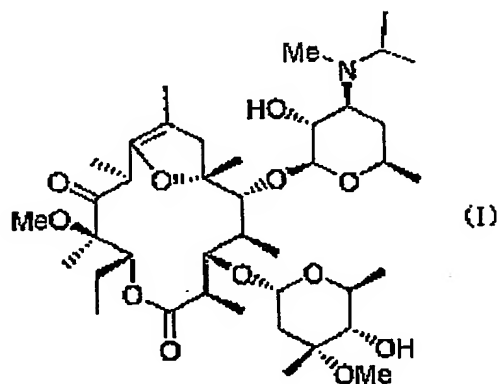
7. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

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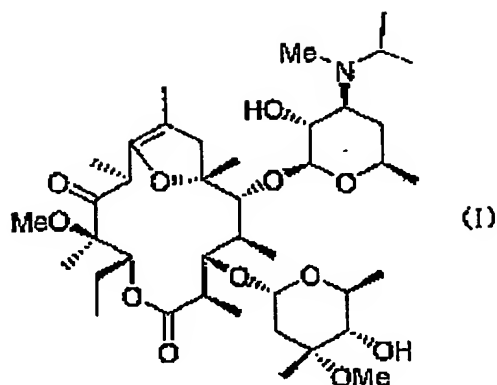
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, wherein said hemifumarate anhydrate is obtained by treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°.

8. A hemifumarate crystal of a compound of formula (I):



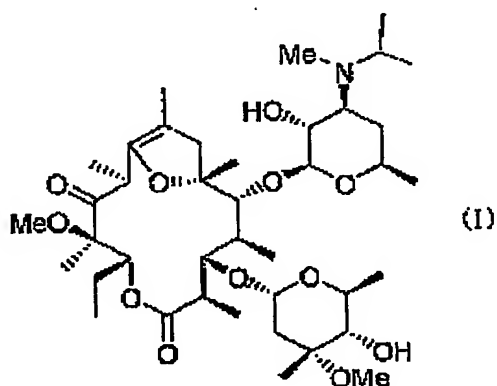
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°.

9. A hemifumarate crystal of a compound of formula (I):



containing acetone and showing strong X-ray diffraction peaks at diffraction angles $2\theta = 5.4^\circ, 10.4^\circ, 10.7^\circ$ and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

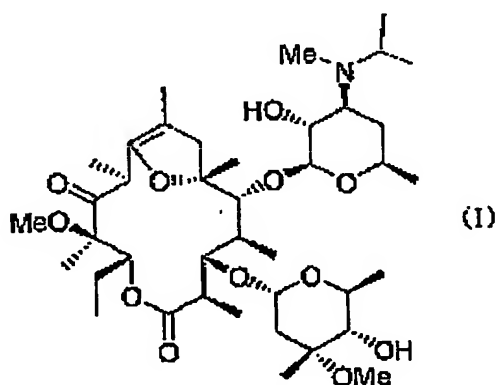
- 5 10. A hemifumarate crystal of a compound of formula (I):



containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles $2\theta = 5.4^\circ, 10.4^\circ, 10.7^\circ$ and 12.1° measured by X-ray diffractometry using

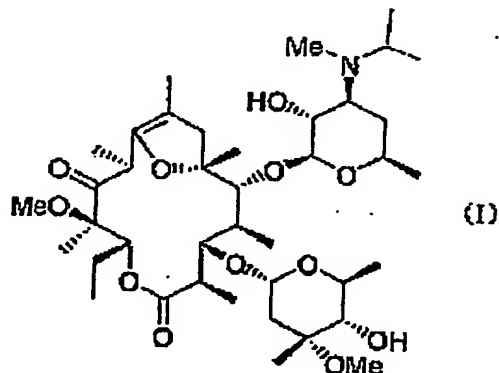
- 10 Cu-K α radiation

11. A hemifumarate crystal of a compound of formula (I):



containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles $2\theta = 5.4^\circ, 10.4^\circ, 10.7^\circ$ and 12.1° measured by X-ray diffractometry using Cu-K α radiation.

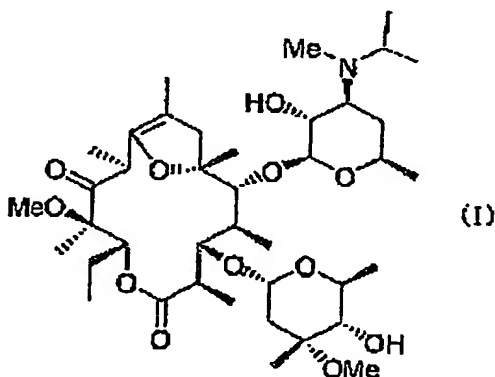
12. (Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



showing strong X-ray diffraction peaks at diffraction angles $2\theta = 5.4^\circ, 10.4^\circ, 10.7^\circ$ and 12.1° measured by X-ray diffractometry using Cu-K α radiation, said process

10 comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of $5.4^\circ, 10.4^\circ, 10.7^\circ$ and 12.1° , to obtain said hydrate.

13. (Amended) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

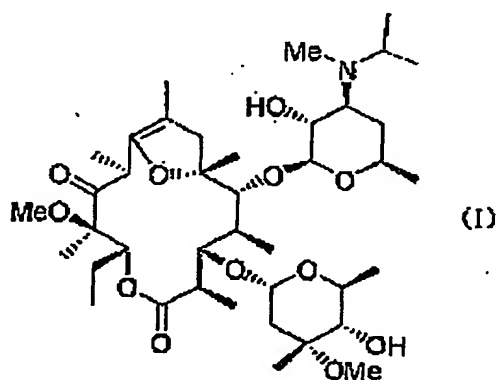


containing acetone and showing strong X-ray diffraction peaks at diffraction angles $2\theta = 5.4^\circ, 10.4^\circ, 10.7^\circ$ and 12.1° measured by X-ray diffractometry using Cu-K α radiation, said process comprising the step of treating a hemifumarate crystal of the

compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°, to obtain said hydrate.

14. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

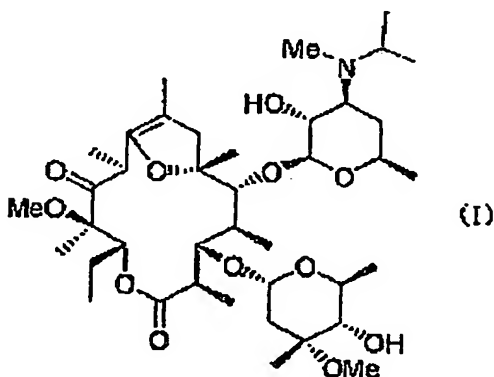
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containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°, to obtain said hydrate.

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15. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

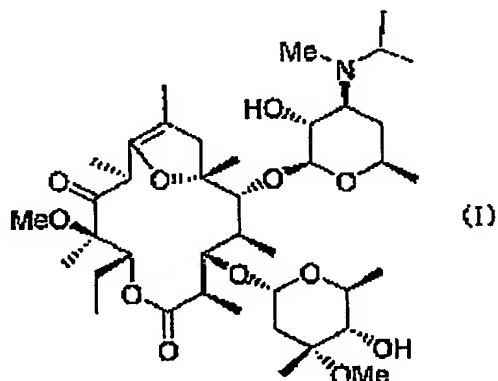


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containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-K α radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-

ray diffraction pattern of 5.4° , 10.4° , 10.7° and 12.1° , to obtain said hydrate.

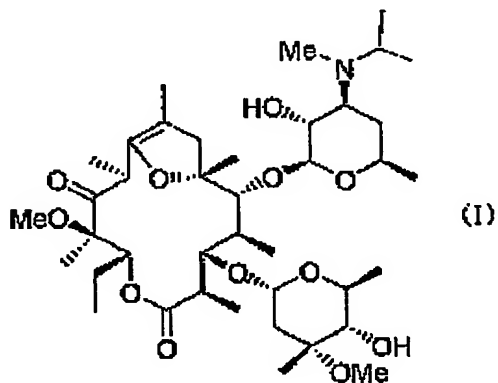
16. A process for preparing a hemifumarate anhydrate of a compound of formula (I):



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characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° , 13.5° and 14.2° , said process comprising the step of obtaining said anhydrate by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.

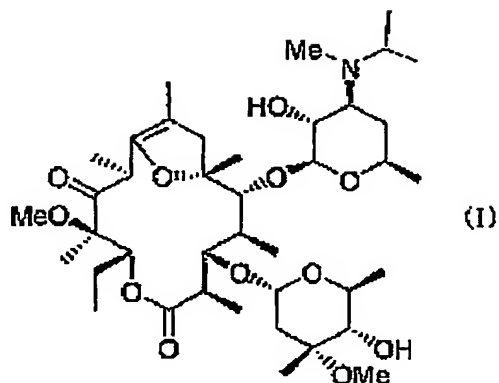
10 17. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



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characterized by 2-theta angle positions in the powder X-ray diffraction pattern of showing strong X-ray diffraction peaks at diffraction angles $2\theta = 7.1^\circ$ and 14.2° , said process comprising the step of obtaining said hydrate by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.

18. A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray
5 diffraction pattern of 7.1°, 13.5° and 14.2°, wherein said anhydrate is obtained by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.